

Notice of References Cited	Application/Control No. 10/790,711	Applicant(s)/Patent Under Reexamination FUJINAWA ET AL.	
	Examiner Benjamin A. Kaplan	Art Unit 2109	Page 1 of 1

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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